

Notice of References Cited	Application/Control No. 10/710,673	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Hiep Nguyen	Art Unit 2816	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,119,045	06-1992	Sato, Yutaka	332/109
*	B	US-5,627,500	05-1997	Wolaver et al.	332/112
*	C	US-6,462,598	10-2002	Okayasu et al.	327/276
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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